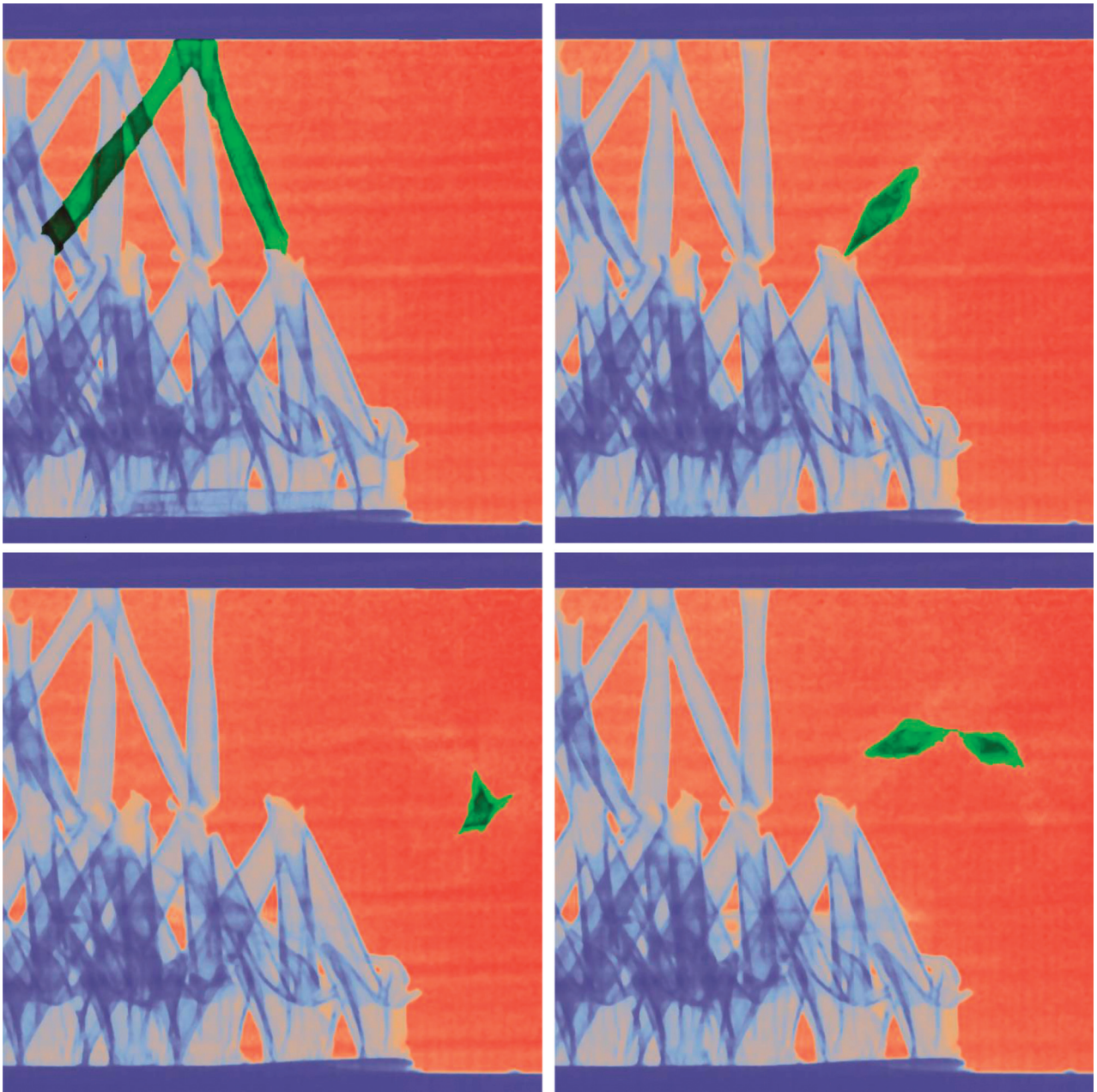


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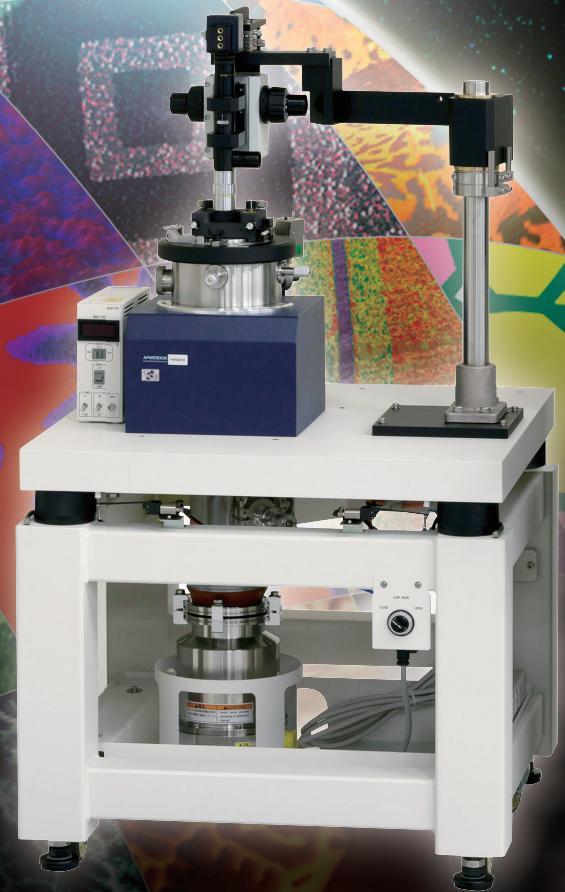
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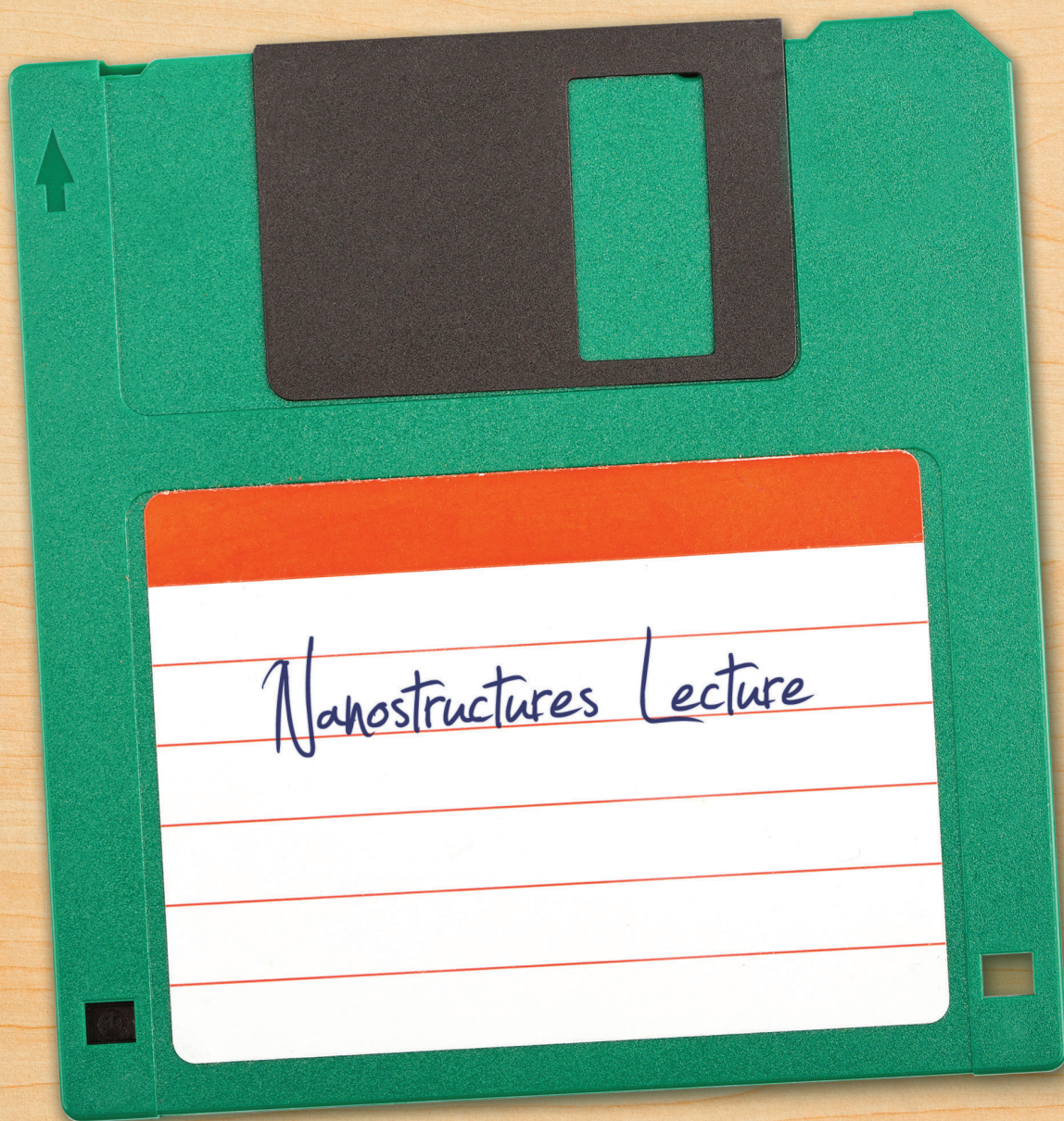
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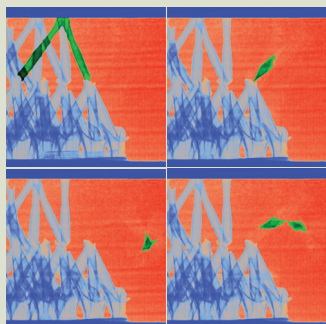


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Clockwise from upper left: successive radiographs, 2 milliseconds apart, of an NiP microlattice during dynamic compression. Fragment in green broke from the sample. Full width=3.4 mm.

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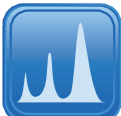
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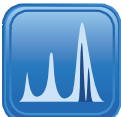
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